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Luminescence and mechanoluminescence of

Ba₄Si₆O₁₆:Eu²⁺, RE phosphors

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Alexis Duval^{1,a)}, Yan Suffren², Mourad Benabdesselam³, Patrick Houizot¹ and Tanguy Rouxel^{1,4}

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ABSTRACT

The luminescence properties of green Ba₄Si₆O₁₆:Eu²⁺, RE (RE = Sc, Y, La-Lu except Pm) phosphors are reported. Their long-lasting phosphorescence is discussed in view of trap depths and concentrations determined from thermally stimulated luminescence experiments. A second emission band centered at 439 nm was evidenced at low temperatures, which stems from the substitution of Eu²⁺ in the two non-equivalent Ba²⁺ sites of Ba₄Si₆O₁₆. The mechanoluminescence properties of Ba₄Si₆O₁₆:Eu²⁺, RE phosphors are described, and a new mechanoluminescence mechanism is proposed, in the case where RE = Ho³⁺ involving a trap

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distribution from 0.694 to 0.924 eV. Mechanical loading (post UV irradiation) induces a decrease in depth of the trap distribution leading to an increase of the luminescence intensity, whereas a drop of the luminescence intensity is observed upon unloading, following the faster release of the charge carriers.

1. INTRODUCTION

The luminescence properties of oxides, oxynitrides and nitrides from the BaO-SiO₂-Si₃N₄ system were reported in the past few years, such as BaSi₂O₅:Eu^{2+ 1 2} (λ_{em} = 500-505 nm), Ba₃Si₅O₁₃₋₈N₈:Eu^{2+ 3} (broad emission bands from 400 to 620 nm), Ba₅Si₈O₂₁:Eu^{2+ 4 5 6} $(\lambda_{em} = 473-480 \text{ nm}), \text{ Ba}_4\text{Si}_6\text{O}_{16}:\text{Eu}^{2+}$ γ 8 9 10 $(\lambda_{em} = 496-515 \text{ nm}), \beta$ -BaSiO₃:Eu²⁺ 6 11 $(\lambda_{em} = 560\text{-}565 \text{ nm}), \text{ Ba}_2\text{SiO}_4\text{:}\text{Eu}^{2+ \ 12 \ 13 \ 14 \ 15} \ (\lambda_{em} = 503\text{-}510 \text{ nm}), \text{ Ba}_3\text{SiO}_5\text{:}\text{Eu}^{2+ \ 6 \ 16 \ 17 \ 18 \ 19}$ $(\lambda_{em} = 585 - 596 \text{ nm}), \text{ BaSi}_2\text{O}_2\text{N}_2\text{:}\text{Eu}^{2+\ 20\ 21\ 22} \ (\lambda_{em} = 498 - 500 \text{ nm}) \text{ or } \text{Ba}_2\text{Si}_5\text{N}_8\text{:}\text{Eu}^{2+\ 23}$ $(\lambda_{em} = 585 \text{ nm})$. This chemical system offers a broad range of emission colors, ranging from blue to orange.

The luminescence properties of Ba₄Si₆O₁₆:Eu²⁺ were reported as early as the 60s, but were mostly studied during the last 15 years with various luminescent centers such as Eu²⁺, Pr³⁺ and $Ce^{3+82425}$. In the crystal, the rare-earths (RE) substitute for Ba^{2+} ions thanks to close ionic radii ²⁶. Its space group is $P2_1/c^{27}$ (a = 12.477 Å, b = 4.685 Å, c = 13.944 Å, β = 93.54°, Z = 2), which is similar to the non-standard $P2_1/a$ formerly used ⁸. Ba₄Si₆O₁₆:Eu²⁺ is a potential phosphor for applications in white light emitting diodes (wLEDs), but synthesis complications including mixed phases like Ba₃Si₅O₁₃ and Ba₅Si₈O₂₁ and high sintering temperatures limit its use 10.

Ba₄Si₆O₁₆ exhibits an intense long-lasting phosphorescence (*LLP*) as well as elastico-mechanoluminescence (EML) ²⁸ when doped with Eu²⁺, in a similar way as BaSi₂O₂N₂. Recall that elastico-mechanoluminescence is the emission of light resulting from an elastic

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deformation. This phenomenon has recently aroused great interest, because of potential applications of mechanoluminescent materials for energy storage or as stress sensors ²⁹. The BaO-SiO₂ binary diagram shows a glass-forming region with a BaO content from 20 to 50 mol. % ³⁰, along with congruent crystallization at given BaO contents. This allowed the formation of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺-containing glass-ceramics exhibiting *EML* thanks to uniformly dispersed active crystals ²⁸. In our previous work (ref. ²⁸), we have reported mechanoluminescence in a new glass-ceramic material mainly consisting Ba₄Si₆O₁₆:Eu²⁺, RE crystalline phase. In this preliminary work, we focused on the choice for the RE co-dopant and we have reported the first mechanical testing results, which revealed significant differences with the behavior of SrAl₂O₄:Eu²⁺, Dy³⁺. The present manuscript provides an in-depth investigation of the role of the co-dopant in the e⁻ trapping energetics and in the physics of the luminescence mechanism. LLP behavior as well as EML properties are related to the characteristics of electron traps within the active crystalline phase. Trap depths and concentrations were determined from thermally stimulated luminescence experiments. Experiments with different loading rates and loading modes allow to propose a mechanism of the *EML* phenomenon in the particular crystal.

2. EXPERIMENTAL

Ba₄Si₆O₁₆:Eu²⁺, *RE* crystals were synthesized starting from dried BaCO₃ (Sigma-Aldrich 99 %), Gd₂O₃, Lu₂O₃, Dy₂O₃, Sc₂O₃, Eu₂O₃ (Sigma-Aldrich 99.9 %), SiO₂ (Sigma-Aldrich 99.5 %), Pr₂O₃, Sm₂O₃ (Fischer 99.9 %), Tb₄O₇ (Fischer 99.998 %), Tm₂O₃ (Alfa Aesar 99.9 %), Yb₂O₃, La₂O₃, CeO₂, Nd₂O₃ (Rhône-Poulenc 99.99 %), Y₂O₃ (Acros 99.99 %), and Ho₂O₃, Er₂O₃ (Rhône-Poulenc 99.999 %). Three series of Ba₄Si₆O₁₆:Eu²⁺, *RE* crystals were studied, with i) a fixed cationic composition: 35 Ba – 60 Si – 3 Eu – 2 *RE* for each *RE*, ii)

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varying Eu ²⁺ : RE ratio for $RE = Pr^3$	⁺ or Ho ³⁺ , and iii) varying Eu ²	$^{4+}+RE$ quantity for $RE = \text{Ho}^{3+}$
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Stochiometric amounts were weighted and grounded during 15 minutes in ethanol in an agate

mortar, and then fired 6 h at 1300 °C in an alumina crucible under a N₂:H₂ = 94:6 reducing

atmosphere. Each specimen was grounded into a fine powder.

The X-ray diffraction (XRD) patterns were collected using a PANalytical X'pert Pro

diffractometer using Cu-Kα radiation (1.5418 Å).

Solid-state excitation and emission spectra were recorded using a Horiba Jobin-Yvon

Fluorolog III fluorescence spectrometer equipped with a Xe lamp operating at 450 W, a

UV-vis-nearIR photomultiplier (Hamamatsu R928, sensitivity 190 - 860 nm), or a

Horiba Jobin-Yvon FluoroMax-4 Plus fluorescence spectrometer equipped with a Xe lamp

operating at 150 W and a UV-vis photomultiplier (Hamamatsu R928, sensitivity

190 – 860 nm). The luminescence spectra were realized on powder samples placed inside the

solid-sample holder fixed in 30° rotation and blocked by a quartz blade.

Emission and excitation spectra of $Ba_4Si_6O_{16}$: Eu^{2+} , Ho^{3+} were recorded from 77 to 300 K in

quartz cuvettes with an optical cryostat (OptistatCF from Oxford Inst.) coupled to a liquid

nitrogen bath under a N2 atmosphere, and from 300 to 380 K in a solid holder using a F-3004

Jobin-Yvon heating Peltier module.

Appropriate filters were used to remove the residual excitation laser light, the Rayleigh

scattered light and associated harmonics from the spectra. All spectra were corrected for the

instrumental response function.

Solid-state UV-visible absorption measurements were obtained with a PerkinElmer Lambda

650 spectrometer using a 60 mm integrated sphere.

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Quant	um yield measurements	were recorded using a G8	GMP integrating sphere	according to:

 $\Phi = (E_c - E_a)/(L_a - L_c)$, where E_c is the integrated emission spectrum of the sample, E_a is the

integrated "blank" emission spectrum, L_a is the "blank" absorption, and L_c is the sample

95 absorption at the excitation wavelength. Samples were introduced in specific capillaries for a

96 G8 integrating sphere, and placed directly inside the integrating sphere.

Rapid luminescence decays were measured directly with the fluorescence spectrometer connected to an additional time-correlated single photon counting (TCSPC) module and a

360 nm pulsed delta diode. Lifetimes and quantum yields are the averages of three independent

00 measurements.

> Luminance, expressed in mcd·m⁻², was measured on a 1.5 cm² sample pellet using a Konica Minolta LS-150 luminancemeter with an integration time of 3 s under UV irradiation $(\lambda_{exc} = 365 \text{ nm})$ in a lab-made black box. The working distance between the luminancemeter and the pellet surface was 45 cm. The irradiation was realized with a lab-made source constituted by 1 LED CUN66B1B from Roithner at 365 nm plugged in a Keysight Technologies E36104B benchtop power supply that provides the desired current (mA) and voltage (V). The incident beam angle is 30° with respect to the normal of the pellet surface and the distance LED-sample is 12 cm. In order to avoid saturation the current was fixed at 90 mA and the voltage at 3.32 V, with an effective power of 0.57 mW·cm⁻².

> Thermally stimulated luminescence (TSL) experiments were performed from 293 to 573 K with a heating rate of 1 $\text{K} \cdot \text{s}^{-1}$. The delay between the end of the UV illumination and reading was 40 s. During heating, the TSL signal was detected by means of a UV-visible photomultiplier tube.

> LLP emission spectra were collected by an optical multichannel analyzer (OMA), consisting of a multimode optical fiber connected to an integrated spectrograph equipped with a CCD array

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covering the range 200-1100 nm. An appropriate grating covering the 200-1100 nm range was used.

LLP and EML experiments were performed on powder/epoxy composites, where each Ba₄Si₆O₁₆:Eu²⁺, RE crystal was mixed with an epoxy resin (obtained by mixing EPOFIX resin Struers and EPOFIX hardener Struers with a 90:10 concentration by weight) with a final powder content of 20 wt. %. Mechanical tests were carried out on disks using a Shimadzu-AGS-X testing machine with a 10 kN load cell and a SiC pusher. The stress σ induced at the center of a disk made in the composite material (epoxy + ceramic powder) during the diametral compression test is expressed as $\sigma = \frac{2P}{\pi dh}$, where P is the load, d the diameter (11.5 mm) and h the height (6 mm) of the disk ³¹. The *LLP* intensity and the *EML* intensity were quantified consistently using a Zyla 5.5 sCMOS Andor Technology high sensitivity camera, by irradiating each sample for 2 minutes using a 365 nm handheld UV light with an effective power of 1.22 mW⋅cm⁻² prior to mechanical loading.

3. RESULTS AND DISCUSSION

3.1 Luminescence properties of Ba₄Si₆O₁₆:Eu²⁺, RE

In a Ba₄Si₆O₁₆ crystal, SiO₄ tetrahedra are corner-sharing to form 2-periodic single chains ²⁷ FIG. 1 (a). Three single chains are linked into triple chains, running along [010] with a 2₁ symmetry, therefore forming 6-membered rings ^{5 7}. Two non-equivalent VIII-coordinated Ba²⁺ sites exist in Ba₄Si₆O₁₆, where Ba(1) is located in between two triple chains while Ba(2) is located between two single chains.

Three series of Ba₄Si₆O₁₆:Eu²⁺, RE crystals were designed as to study both the incidence of the various RE co-doping, the Eu:RE ratio and the Eu+RE quantity on the luminescence properties.

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XRD patterns confirmed the sole crystallization of Ba₄Si₆O₁₆ in each sample FIG. 1 (b). The excitation spectra were similar with a change of RE, extending up to 420 nm with a maximum at $\lambda_{max} = 329$ nm FIG. 2 (a). Just like Ba₅Si₈O₂₁:Eu²⁺, Dy^{3+ 5}, such broad excitation spectra make it possible to activate Ba₄Si₆O₁₆:Eu²⁺, *RE* phosphors simply through sunlight irradiation.

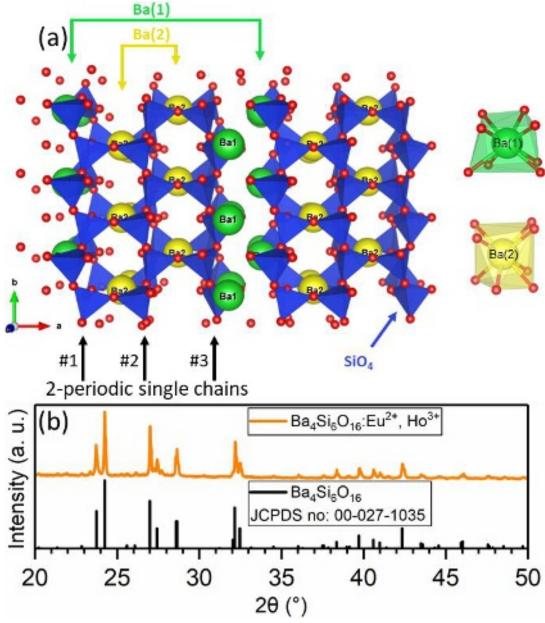


FIG. 1. (a) Crystal structure of Ba₄Si₆O₁₆. Green, yellow, and blue polyhedra correspond to Ba(1), Ba(2), and Si-based polyhedra respectively. The local coordination of the Ba(1) and

Ba(2) sites with the oxygen atoms (red) is shown (b) Typical *XRD* pattern of a Ba₄Si₆O₁₆:Eu²⁺,

47 RE crystal, here when $RE = \text{Ho}^{3+}$ (orange), and the standard XRD pattern of Ba₄Si₆O₁₆ (black).

An excitation wavelength of 365 nm was chosen for the following measurements to remain consistent with the *EML* experiments discussed later in the article. The emission spectra consist of a broad emission band from 400 to 700 nm characteristic of the $4f^65d^1 \rightarrow 4f^7$ transition of Eu^{2+} , with a maximum ranging from 516 to 526 nm. While its position is *RE*-dependent, no conclusions could be obtained regarding its trend. All Ba₄Si₆O₁₆:Eu²⁺, *RE* crystals exhibited a green emission, with CIE coordinates x = 0.302, y = 0.478 when $RE = Ho^{3+}$ FIG. 2 (b).

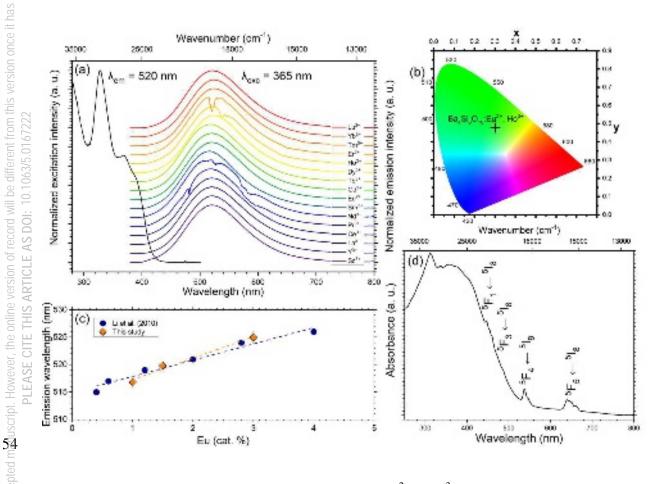


FIG. 2. (a) Excitation spectrum of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺, and emission spectra of Ba₄Si₆O₁₆:Eu²⁺, *RE* crystals (b) CIE chromaticity coordinates of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ (c) Dependence of the emission wavelength on the europium concentration in Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺

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crystals	with	a	fixed	Eu:Ho	ratio,	and	in	$Ba4\text{-y}Eu_{y}Si_{6}O_{15.85}N_{0.1}$	crystals	7	(d)	Absorption
spectrun	n of B	a4\$	Si ₆ O ₁₆ :	:Eu ²⁺ , H	[o ³⁺ .							

In the literature, the λ_{max} position of the broad emission band of Ba ₄ Si ₆ O ₁₆ :Eu ²⁺ , RE crystals
ranges from 494 up to 526 nm. Indeed, its position is slightly redshifted when the europium
concentration is increased 7 . Here, the emission maximum of Ba ₄ Si ₆ O ₁₆ :Eu ²⁺ , Ho ³⁺ crystals with
a fixed Eu:Ho ratio but with increasing europium concentrations from 1 to 3 cat. % increases
from 517 to 525 nm FIG. 2 (c). Typically, $\mathrm{Eu^{2+}}$ concentrations from 0.08 to 1.5 cat. % lead to
emission maxima ranging from 495 to 505 nm 9 10 32 33 , while higher concentrations up to
4 cat. % lead to a maximum emission at 526 nm ⁷ . Hence, the reported emission color of
Ba ₄ Si ₆ O ₁₆ :Eu ²⁺ , RE phosphors ranges from bluish-green to green, and can easily be tuned by
choosing the right RE co-doping as well as Eu^{2+} concentration. The higher the Eu^{2+}
concentration is and the smaller the distance between the europium ions becomes, which means
that the probability of energy transfer from higher-energy 5d levels Eu ²⁺ ions to lower-energy
5d levels Eu ²⁺ ions increases, resulting in the end in an emission band shifting towards longer
wavelength ⁹ .

Several absorption peaks were observed when $RE = Pr^{3+}$, Nd^{3+} , Ho^{3+} , or Er^{3+} , with positions at 538, 547, and 638 nm in the case of Ho^{3+} corresponding to transitions from the ground state 5I_8 to 5F_4 , 5S_2 , and 5F_5 respectively 34 . The absorption spectrum of Ba₄Si₆O₁₆:Eu²⁺, Ho^{3+} revealed both the broad absorption band of Eu²⁺ at short wavelength (< 400 nm), as well as various Ho^{3+} intraconfigurational transitions FIG. 2 (d). The absorption and the quantum efficiency were estimated at 79 ± 10 % and 17 ± 10 % respectively with λ_{exc} = 365 nm. Li *et al.* 7 reported a similar absorption (80 %) but a considerably higher quantum efficiency (46 %) in Ba_{3.8}Eu_{0.2}Si₆O_{15.85}N_{0.1}.

The luminescence decay was studied over a duration of 6000 ns for $RE = Ho^{3+}$ and Er^{3+} . It can

be fitted using equation (1):

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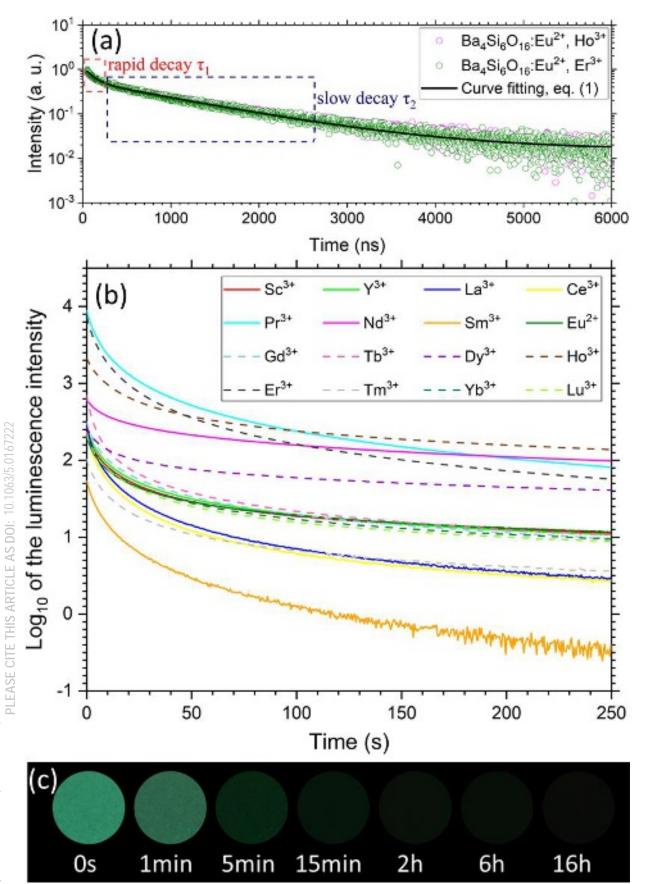
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$$I(t) = A_1 \exp\left(-\frac{t}{\tau_1}\right) + A_2 \exp\left(-\frac{t}{\tau_2}\right)$$
 (1)

Where I(t) is the luminescence intensity at a given time t, A_1 and A_2 are constants, and τ_1 and τ_2 are time constants describing the luminescence decay. Two regimes are observed in the beginning for a duration of about 200 s: a rapid one at t < 200 ns followed by a slower one, corresponding respectively to $\tau_1 = 0.107 \pm 0.002$ µs and $\tau_2 = 1.140 \pm 0.004$ µs FIG. 3 (a), suggesting that in both cases the luminescent center is Eu²⁺ while the RE act as sensitizers. Yang et al. ¹⁰ also identified two lifetimes in Ba₄Si₆O₁₆:Eu²⁺, RE crystals when $RE = Eu^{2+}$, Dy³⁺, or Ho³⁺, however these lifetimes are significantly larger than those reported here ($\tau_1 = 4 \mu s$ and $\tau_2 = 30.3 \,\mu\text{s}$). In addition, Chen et al. 8 observed a decrease of the effective decay time with an increase of the europium content in Ba_{3.86-y}Si₆O₁₆:0.07Ce³⁺,0.07Li⁺, yEu²⁺, which suggests that a variation of the Eu²⁺:RE ratio and/or Eu²⁺+RE quantity induces a visible change of the specimens lifetime. This was attributed to energy transfers between RE^{3+} co-dopants and Eu²⁺. However, the kinetics of the *LLP* decay depends significantly on the selected *RE* FIG. 3 (b). While the steady-state luminescence (SSL) intensity is roughly similar whatever the RE, the LLP intensity changes significantly. For example, it is increased by two orders of magnitude as Ho³⁺ substitutes Sm³⁺. The RE leading to the highest LLP intensity at times smaller than 250 s are, in descending order, Ho³⁺ Nd³⁺ Pr³⁺ and Er³⁺. The luminescence of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ is visible to the naked eye beyond a day after the excitation source is stopped. FIG. 3 (c) displays photographs at various times of the *LLP* decay in the case of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺.

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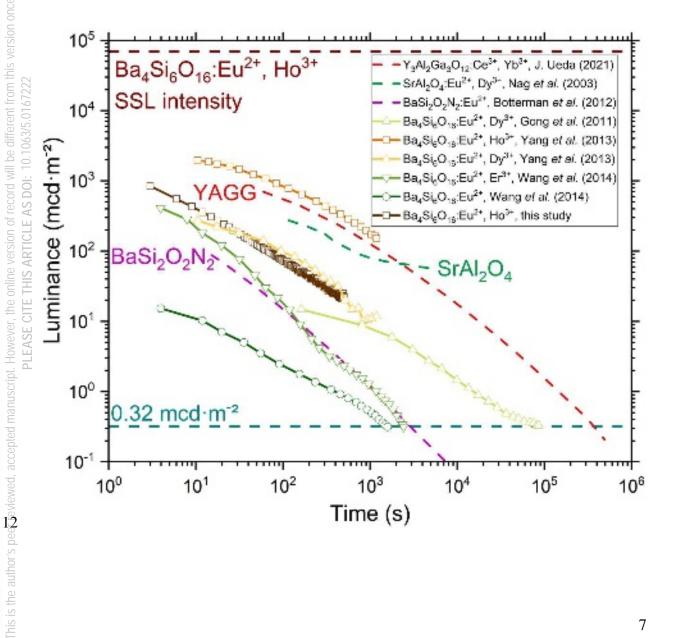
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FIG. 3. (a) Rapid-decay of Ba₄Si₆O₁₆: Eu²⁺, RE crystals for RE = Ho³⁺ or Er³⁺ (b) LLP decay of Ba₄Si₆O₁₆:Eu²⁺, RE crystals (c) Photographs of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ taken at various times after the excitation source is stopped, excited beforehand 2 minutes by a 365 nm UV light. Each disk is 1 cm wide.

The afterglow intensity of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ drops by two orders of magnitude as soon as the excitation source is stopped FIG. 4. It is smaller by about 80 % than the one of the well-known SrAl₂O₄:Eu²⁺, Dy³⁺. Yang et al. ¹⁰ reported a significantly higher afterglow intensity of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺, well above those of previously reported Ba₄Si₆O₁₆:Eu²⁺, RE crystals and noticeably stronger than that of SrAl₂O₄:Eu²⁺, Dy³⁺.



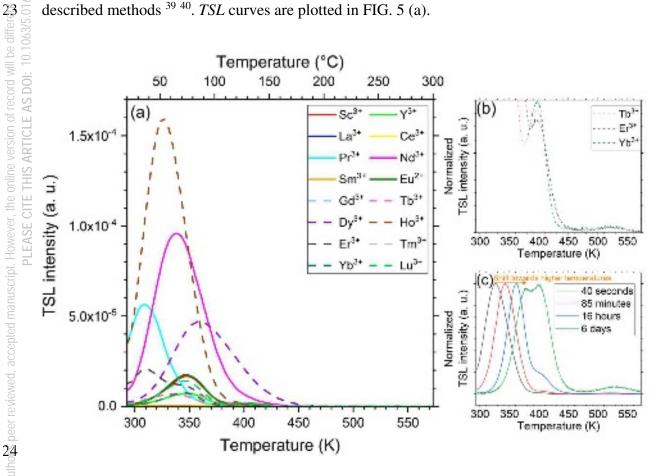
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FIG. 4. Luminance of Ba₄Si₆O₁₆:Eu²⁺, *RE* crystals reported here or in the literature ¹⁰ ³² ³³, as well as that of well-known phosphors such as Y₃Al₂Ga₃O₁₂:Ce³⁺, Yb³⁺ (*YAGG*) ³⁵, SrAl₂O₄:Eu²⁺, Dy³⁺ ³⁶, BaSi₂O₂N₂:Eu²⁺ ³⁷. The *SSL* intensity of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ is also indicated.

TSL experiments provide key elements to better understand the LLP intensity and decay, such as the trap depths and distributions. Trap depth E and concentration n_0 can be calculated from the TSL intensity I(T) according to 38 :

$$I(T) = \left[\left(\frac{(l-1)s}{\beta} \right) \times \int_{T_0}^T \exp\left(-\frac{E}{k_B T} \right) dT + 1 \right]^{-\frac{l}{l-1}} s n_0 \exp\left(-\frac{E}{k_B T} \right)$$
 (2)

Where k_B is the Boltzmann constant, T the temperature, l the kinetic order, s the frequency factor, and β the heating rate (1 K·s⁻¹). E, l and s were deduced according to previously described methods ³⁹ ⁴⁰. TSL curves are plotted in FIG. 5 (a).



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(b) Zoom-in of the TSL measurements highlighting the recurring 398 and 523 K TSL peaks (c)

27 TSL measurements of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ carried out with various delay times.

In Ba₄Si₆O₁₆:Eu²⁺, RE crystals, three recurring TSL peaks were observed FIG. 5 (a) and FIG. 5

29 (b). The first one lies in the 303-363 K region, while the second and third ones are

systematically located at temperatures of 398 K and 523 K respectively. The only exceptions

31 are i) $RE = Dy^{3+}$, for which the width of the first peak suggests two combined peaks ii) Er^{3+} ,

which also exhibits two peaks in the 303-363 K region, and iii) Tm³⁺ that exhibits a third peak

at 473 K. Such a recurrence in the peak position hints that the nature of those traps is similar

regardless of the RE co-doping. Further experiments would be required to elucidate the physical

and structural origins of these electron traps.

In addition, TSL experiments performed with different delay times with $RE = Ho^{3+}$ evidenced a gradual shift from the first TSL peak towards higher temperatures FIG. 5 (c), which implies that at least for this co-dopant there is actually a distribution of trap depths rather than a discrete energy level. This is consistent with preliminary DFT calculations performed on the Ba₄Si₆O₁₆ crystal, which also show the presence of a distribution of energy levels arising from oxygen vacancies ²⁸. This distribution of energies would extend from at least $E_{C_3} = 0.694$ to $E_{C_1} = 0.924 \text{ eV}$, where C_3 is the top and C_1 the bottom of the trap distribution. It is slightly shallower than that reported by Yang et al. (which extended from 0.602 to 1.156 eV) 10, where its deepness was possibly overestimated because of the close second TSL peak at 398 K. As a matter of fact, short (< 500 s) and long time (up to 60000 s) luminescence decay measured at the peak emission wavelength would suggest that this distribution is close to a gaussian form FIG. 6 41 42 43 44. It is noteworthy that RE co-doping in Ba₄Si₆O₁₆ does not always lead to a

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distribution of trap depths. For example, Dy^{3+} co-doping does not induce a shift of the first TSL peak position with increasing delay times 10 .

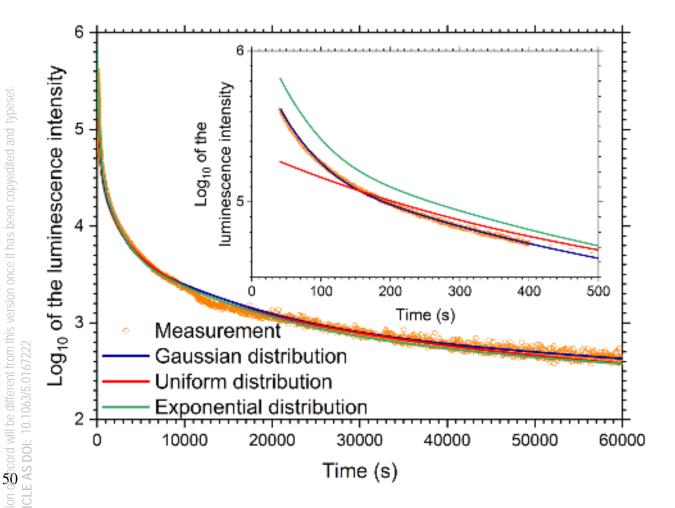


FIG. 6. *LLP* decay (< 60000 s) of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ fitted with various distribution shapes. The inset shows the *LLP* decay at short times (< 500 s).

In order to get more insight into the *LLP* behavior of Ba₄Si₆O₁₆:Eu²⁺, *RE* crystals at the scale of a few minutes, only traps with a depth of 1 eV at most need to be considered, which correspond to the first peak in the 303-363 K region. Thus, the second and third peaks, which correspond to deeper traps are excluded from this study. The high sensitivity camera used for *LLP* experiments does not allow to quantify the luminescence intensity immediately after the excitation source is stopped. Therefore, the luminescence intensity at an arbitrarily chosen time of 250 s was used as a reflection of the *LLP* lifetime. As can be seen in FIG. 7, there is an

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excellent agreement between the *LLP* behavior and the traps depths and concentrations as determined from the spectra in FIG. 5 by means of equation (2): the Ba₄Si₆O₁₆:Eu²⁺, *RE* crystals with the strongest afterglow intensity are the ones with the largest concentrations of traps with depths ranging from 0.65 to 0.85 eV, a region where the relaxation kinetics to the fundamental state is of the order of a few minutes to several days.

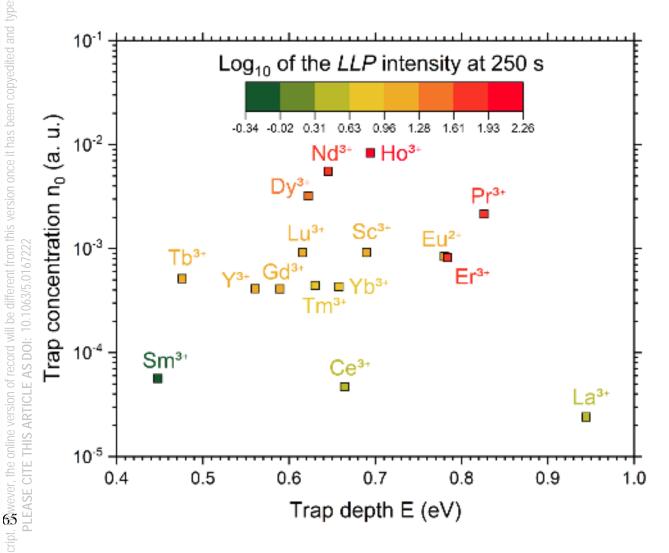


FIG. 7. Trap depth and concentration of the various Ba₄Si₆O₁₆:Eu²⁺, *RE* crystals determined from equation (2).

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As europium ions are incorporated in Ba ₄ Si ₆ O ₁₆ crystals, Eu ²⁺ will occupy the two
non-equivalent Ba2+ sites. It was proposed that, because both Ba(1) and Ba(2) sites are
coordinated by eight oxygen atoms ²⁷ , the two europium ions environments are relatively
similar, in agreement with the fact that two broad emission bands with close emission maximum
are observed ⁷ ¹⁰ ³² . Indeed, while the 4f electrons of divalent europium are quite insensitive to
their surroundings, this is not the case of the 5d electrons ³² . Consistently, the broad emission
band could be deconvoluted into two bands at $\lambda_{max} = 500$ and 550 nm, corresponding to the
two non-equivalent europium sites, namely Eu(1) and Eu(2) 32. This is supported by i) a shift
of the broad emission band maximum towards longer wavelength when the delay time
increases, which suggests the existence of two different lifetimes for each site 32, and ii) a
significantly different excitation spectra when $\lambda_{em} = 500$ or 550 nm.

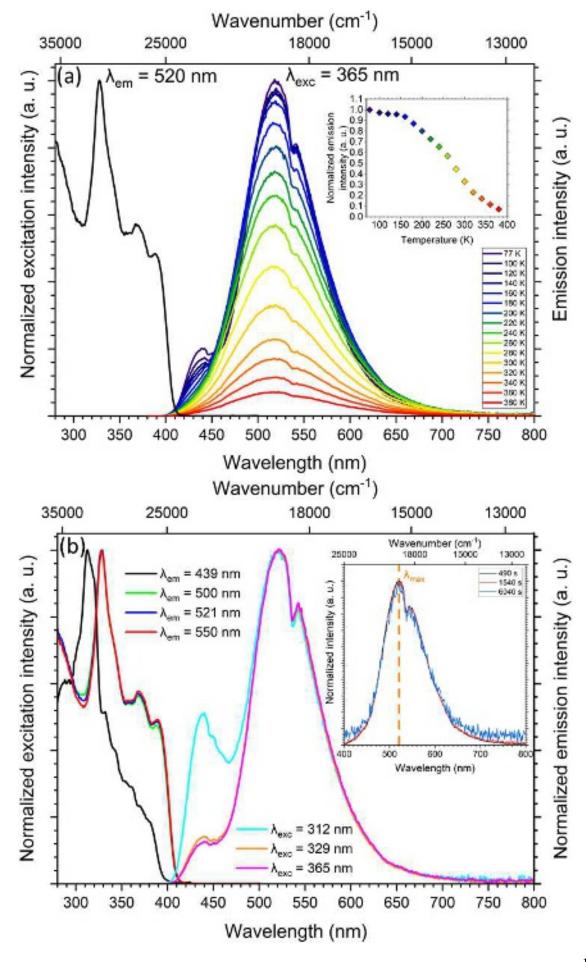
Thermoluminescence experiments performed in this work from 77 to 380 K support another interpretation. When the emission spectra are measured at temperatures as low as 77 K, one can observe a second emission band appearing at $\lambda_{max} = 439$ nm, in addition to the green emission band at λ_{max} = 521 nm FIG. 8 (a). The intensity of this blue emission band gradually decreases up to 200 K where it is no longer visible, while the thermal quenching of the green emission band starts at 160 K but is not yet completed at 380 K. Furthermore, excitation spectra collected at 77 K with λ_{em} = 500, 521, or 550 nm are identical FIG. 8 (b), but all-three were notably different from the one obtained with $\lambda_{em} = 439$ nm. Indeed, the latter is shifted towards shorter wavelengths and its behavior in the 330-400 nm region is clearly unalike. This is in contradiction with what was previously reported ³². This suggests that i) the blue and green emission bands are of different nature, which is clearly outlined when $\lambda_{exc} = 312$ nm, and ii) the green emission band is not composed of two subsequent emission bands.

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FIG. 8. (a) Excitation spectra measured at 77 K and emission spectra measured at various temperatures (20 K steps) of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺. The inset shows the emission intensity at various temperatures. (b) Excitation and emission spectra of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ at 77 K. The inset shows the *LLP* emission spectra at ambient temperature various times after the excitation source is stopped.

The interpretation proposed in this work is supported by emission spectra measured at various times after the excitation source is stopped, where no shift of the emission maximum was observed FIG. 8 (b), which was already noted in another study ⁴⁵. The previously observed shift is likely resulting from the presence of β -BaSiO₃ as a secondary phase, which is revealed by the presence of a peak on the *XRD* pattern at 26° FIG. 1. The persistent luminescence properties of this crystal are known ¹¹ and an emission maximum at $\lambda_{max} = 560$ nm was identified, which explains the shift of the emission maximum towards longer wavelengths with time.

It is thus concluded that the two non-equivalent Eu^{2+} sites are sufficiently different to give birth to two emission bands at low temperatures. Indeed, the Ba(1) polyhedron is more distorted than the Ba(2) one ²⁷, so that an 82 nm difference between the two emission bands maximum is observed. It was proposed that the higher distortion degree of the Ba(1) polyhedra would result in a weaker crystal field of Ba(1) than that of Ba(2) ¹⁰, thus, the broad emission band of Eu(1) would be in a shorter wavelength region than that of Eu(2) ⁴⁶, *i. e.* the blue emission band would correspond to Eu(1) and the green one to Eu(2). However, it is still not clear as to why the thermal quenching of Eu(1) occurs at much lower temperatures than that of Eu(2).

The thermoluminescence behavior of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ is very similar to that of monoclinic SrAl₂O₄:Eu²⁺, Dy³⁺. In the latter, a blue emission band also appears at low temperatures ($\lambda_{max} = 445 \text{ nm}$) which arises from the presence of two non-equivalent Sr²⁺ sites in the crystal structure ⁴⁷. In addition, the asymmetric green emission band of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ is shifted

to larger wavelengths just like the green emission band ($\lambda_{max} = 520 \text{ nm}$) of strontium aluminate. In this latter case, this was discussed by Botterman et al. 47 in terms of the centroid shift and crystal field splitting.

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3.3 Mechanoluminescence properties of Ba₄Si₆O₁₆:Eu²⁺, RE

The EML response of Ba₄Si₆O₁₆:Eu²⁺, RE/epoxy composites, obtained by subtracting the LLP intensity as recorded at rest (i. e. at $\sigma = 0$ MPa) to the mechanically-loaded specimen, was characterized by means of the diametral compression tests FIG. 9 (a). Each test was performed with a $0.37 \text{ MPa} \cdot \text{s}^{-1}$ stress rate. It is recalled that the *EML* intensity is proportional to both the stress and the stress rate ⁴⁸. In a similar way as with the previous *LLP* measurements, the *RE* co-doping has a pronounced effect on the intensities of the EML signal. The largest intensities are obtained with $RE = \text{Ho}^{3+}$, Pr^{3+} , Er^{3+} , or Nd^{3+} FIG. 9 (b). The mechanical stress was applied 90 s after the excitation source was stopped, as longer delays resulted in smaller *EML* intensity. This suggests that the charge carriers involved in the *EML* of Ba₄Si₆O₁₆:Eu²⁺, *RE* crystals slowly recombine with the luminescent center with time, and are thus also participating in the *LLP* at the scale of several minutes/hours.

There seems to be a strong connection between the *EML* intensity and the *LLP* intensity FIG. 9 (c). Various mechanisms were proposed to explain the mechanically-induced luminescence ²⁹, among which those involving piezoelectricity are the most popular. It is supposed that, as a stress field is applied, the trap depths are changed thanks to piezoelectricity, ultimately altering the charge carriers recombination kinetics. Although Ba₄Si₆O₁₆ is centrosymmetric (space group $P2_1/c$) and should therefore not exhibit piezoelectricity, centrosymmetry might be broken at the local scale by the presence of defects, so that piezoelectricity can subsequently be observed ²⁹. In Ba₂Si₂O₂N₂:Eu²⁺, the stress is assumed to induce a decrease of a trap depth

leading to an increased luminescence intensity ²⁰. In the SrAl₂O₄:Eu²⁺, Dy³⁺ compound, a mechanism with three discrete traps allowed to explain an increase in the luminescence intensity both during the loading and the unloading stages ⁴⁹. This correlation is therefore consistent with this latter mechanism: a larger trap concentration with depths ranging from 0.65 to 0.85 eV is assumed i) to result in a stronger *LLP* intensity, but also ii) in a stronger *EML* intensity, as more charge carriers will be able to recombine with the luminescent center when the trap depth decreases.

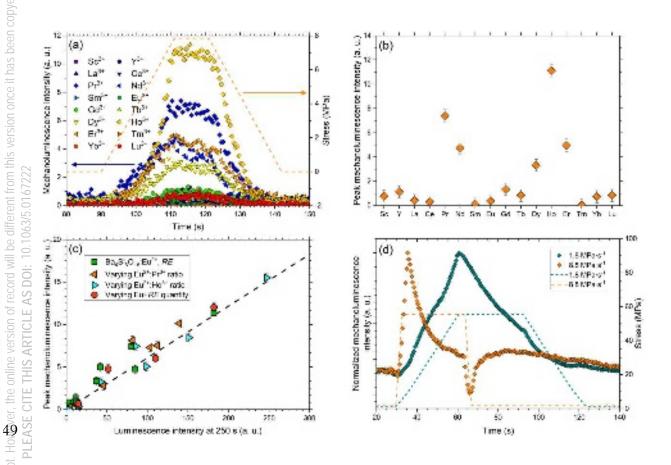


FIG. 9. (a) *EML* intensity of Ba₄Si₆O₁₆:Eu²⁺, *RE*/epoxy composites (b) Peak *EML* intensity of Ba₄Si₆O₁₆:Eu²⁺, *RE*/epoxy composites (c) Peak *EML* intensity plotted as a function of the luminescence intensity at 250 s (d) *EML* intensity of Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺/epoxy composite with stress rates of 1.8 and 8.8 MPa·s⁻¹.

Regarding the Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ compound, its *EML* behavior contrasts with the one of SrAl₂O₄:Eu²⁺, Dy³⁺. It is particularly outlined with high stress rates (here with 8.8 MPa·s⁻¹),

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where *EML* is more intense and therefore better resolved FIG. 9 (d). It is noteworthy that the *EML* behavior of the Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺/epoxy composite is identical to that of a mechanoluminescent glass-ceramic with the same cationic composition ²⁸. The mechanical loading and its holding lead to an increase in the luminescence intensity, while the unloading leads to a decrease of the luminescence intensity. Changes in irradiation time lead to an increase in both the luminescence and the mechanoluminescence intensity.

In particular, TSL experiments provide insight into the EML mechanism. Based on the existence of an electron trap distribution, we can propose an energy level scheme for Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ FIG. 10. Although the identified charge carriers (holes and/or electrons) involved in the afterglow of Ba₄Si₆O₁₆:Eu²⁺, RE phosphors are still unknown ³², it is assumed that electrons are the key players. Traps corresponding to the 398 K and 523 K TSL peaks are too deep to contribute to the EML effect. The Eu²⁺ ions electronic configuration changes from the ground state 4f⁷ to the 4f⁶5d¹ excited state under UV light. Then, the electron can escape to the conduction band and eventually reaches energy levels located in the band gap, leaving behind Eu³⁺ ions. The main effect of the mechanical loading is to change the depth of the trap distribution, i. e. the C_3 and/or the C_1 trap depth decreases (FIG. 10 illustrates the scenario where the depth of the whole trap distribution decreases). The recombination probability is therefore higher and an increase of the luminescence intensity follows. However, the mechanical loading empties the stocked charge carriers at a much higher rate than it would have at rest. As a matter of fact, a smaller luminescence intensity is observed after the stress is relieved. This model provides an explanation to the observed *EML* during both mechanical loading and unloading, in consistency i) with the EML mechanisms involving changes in trap depths through piezoelectricity, and ii) the decrease in the *EML* intensity with long delays prior to mechanical loading in Ba₄Si₆O₁₆:Eu²⁺, *RE* crystals.

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Eu(2) $4f^{6} 5d^{1}$ CB C_{3} C_{1} C_{3} C_{1} Eu^{2+}



FIG. 10. Energy level scheme of $Ba_4Si_6O_{16}$: Eu^{2+} , Ho^{3+} under mechanical stress. For the sake of clarity, the trap distribution is shown as a continuous succession of trap depths.

4. CONCLUSION

The luminescence properties of Ba₄Si₆O₁₆:Eu²⁺, *RE* crystals, as well as their *EML* properties, were studied. A change in the *RE* co-doping leads to small changes in the emission wavelength, but to dramatic changes in the *LLP* behavior and *EML* intensity. The incidence of the *RE*

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co-doping was put into perspectives with trap depths and concentrations determined from TSI
measurements. Exact definition of co-doping and Eu ²⁺ concentration allows to tune the
emission color and lifetime of Ba ₄ Si ₆ O ₁₆ :Eu ²⁺ , RE phosphors. When $RE = Ho^{3+}$, the LLR
duration extends beyond a day.

Emission spectra measured at low temperatures revealed a second emission band $(\lambda_{max} = 439 \text{ nm})$ in addition to the green emission band $(\lambda_{max} = 521 \text{ nm})$. They stem from Eu²⁺ ions located in the two non-equivalent Ba2+ sites in Ba4Si6O16, in a similar way as in SrAl₂O₄:Eu²⁺, Dy³⁺.

TSL experiments unveiled a trap distribution from 0.694 to 0.924 eV in Ba₄Si₆O₁₆:Eu²⁺, Ho³⁺ that allowed, with EML experiments, to build an energy level scheme of the ongoing EML mechanism. Mechanical loading decreases the depth of the trap distribution, resulting in a faster release of the charge carriers and ultimately in an increase of the luminescence intensity. During unloading, the trap distribution returns to its initial position but with significantly less charge carriers, which is exhibited by a drop of the luminescence intensity i. e. by a negative EML intensity.

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AUTHOR DECLARATIONS

Conflict of Interest

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Author	Contr	·ihutio	ne

The authors have no conflicts to disclose.

13	Alexis Duval: Conceptualization (lead); Data curation (lead); Investigation (lead);
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b)ed	Data curation (lead); Investigation (equal); Methodology (equal); Writing – review & editing
beed Scopyed	(equal). Mourad Benabdesselam: Conceptualization (equal); Data curation (lead);
19	Investigation (equal); Methodology (equal); Writing – review & editing (equal). Patrick
Sion Stee	Houizot: Conceptualization (equal); Investigation (equal); Methodology (equal); Supervision
his (F)	(equal); Writing – review & editing (equal). Tanguy Rouxel: Conceptualization (equal);
(M erent fro 以 this 063/5.0167222	Methodology (equal); Supervision (equal); Writing – review & editing (equal).
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DATA AVAILABILITY

The data that support the findings of this study are available within the article and from the corresponding author upon reasonable request.

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